



## SEMI® International Standards Program

### Compound Semiconductor Technical Committee Meeting

Virtual Meeting (Videoconference)

**Wednesday 25<sup>th</sup> Jul 2023,  
16:30 CEST / 7:30 am PDT / 23:30 J**

V1 19.07.2023

Co-chairs:

- [Dr. Arnd-Dietrich Weber, SiCrystal](#)
- [N.N](#)

#### European Compound Semiconductor Committee Meeting (Virtual Meeting)

16:30	<b>Welcome and Self-Introductions</b>	<b>all</b>
16:40	SEMI Standards Overview and Legal Reminders	SEMI Staff
16:45	Review of the minutes and action items from the previous meeting	SEMI Staff
16:50	Task Force Reports (~5 minutes each) <ul style="list-style-type: none"><li>• SiC-Task Force</li><li>• 5-year Review (M46, M63, M75) Task Force</li><li>• XRT Test Method for SiC -Task Force</li></ul>	A. Weber H.C. Alt C. Kranert
17:00	Ballot Review 6870 (new standard) (Test Method for Quantifying Basal Plane Dislocation Density in 4h Sic by X Ray Diffraction Topography/Imaging)	C. Kranert
17:20	Ballot Review 7053 (Line item revision of M63) Test Method for Measuring the Al Fraction in AlGaAs on GaAs Substrates by High Resolution X-Ray Diffraction	H.C. Alt
17:40	New Activity: 5y review: SEMI M81-0418: Guide to Defects Found in Monocrystalline Silicon Carbide Substrates	A. Weber
17:50	Compound Materials Liaison Reports <ul style="list-style-type: none"><li>• North America</li><li>• Japan</li><li>• China</li></ul>	SEMI Staff
18:10	New Business: <ul style="list-style-type: none"><li>• Open discussion</li></ul>	N.N.
18:15	Any Other Business / Questions	A. Weber
18:20	Next Meetings	
18:30	End	